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APPLICANT

Hans Tandler et al.

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INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

U.S. PATENT DOCUMENTS

Examiner Initial	Cite No. <sup>1</sup>	Patent Number	Issue Date	Patentee	Class/ Subclass	Filing Date
JW		5,187,702	February 16, 1993	Naomasa Takahashi		December 27, 1990
JW		5,365,296	November 15, 1994	Junichi Murakami et al.		October 29, 1991
JW		5,563,853	October 8, 1996	Kazuyoshi Ishii		November 2, 1995
JW		5,612,740	March 18, 1997	Chung-Shing Lee et al.		August 16, 1995
JW		5,623,372	April 22, 1997	Tsutomi Matsui		June 14, 1995

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

Examiner Initial	Document Number	Publication Date	Country or Patent Office	Class/ Subclass	Translation Yes/No
JW	DE 26 11 639	9/22/77	GERMANY		*No
JW	DE 43 15 630	10/11/94	GERMANY		*No
JW	DE 29 602202	8/29/96	GERMANY		*No
JW	DE 38 08 510	2/2/89	GERMANY		*No
JW	DE 42 24 824	1/28/93	GERMANY		*No
JW	EP 646 769	4/5/95	EUROPE		*No
JW	EP 744 650	11/27/96	EUROPE		*No

OTHER DOCUMENTS

(Including Author, Title, Date, Relevant Pages, Place of Publication)

Examiner Initial	Cite No. <sup>1</sup>	
JW		*English Abstract of DE 26 11 639
JW		*English Abstract of DE 43 15 630
JW		*English Abstract of DE 29 602202
JW		*English Abstract of DE 38 08 510
JW		*English Abstract of DE 42 24 824
JW		*English Abstract of EP 646 769
JW		*English Abstract of EP 744 650
JW		Knaurs Lexikon der Technik 1988, p. 59 with English Abstract

EXAMINER	DATE CONSIDERED
Winstedt, J. <i>Jennifer Winstedt</i>	5/29/02

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to applicant.